Novel Designs of Indium Gallium Nitride Based Intermediate Band Solar Cells Through Graded Structures



Graduate School & International Education Student: Manal Aldawsari Degree: Ph.D., July 2021 Microelectronics-Photonics Major Professor: Dr. Morgan Ware Nanoscience & Engineering **Photonics** Approach Background/Relevance Deposit InGaN on sapphire substrates using MBE. Single junction solar cells reached their maximum theoretical • efficiency so other materials and novel structures must be • Fabricate InGaN solar cells using photolithography techniques, dry established. etching, and metallization. InGaN has a direct band gap from 0.7 eV to 3.4 eV that covers Structure characterization using atomic force microscopy (AFM), ٠ the solar spectrum and the novel designs of InGaN solar cells and transmission electron microscopy (TEM). through graded structures will enhance the photovoltaic Photoluminescence (PL) measurements and Current-Voltage ٠ performance. measurements. Innovation Absorbance, Reflectance and Transmission spectroscopy • measurements will be performed. Use full graded In_xGa_{1-x}N layer starting GaN and grade down to InN. Then, reverse the grading going up to InGaN (30%). External quantum efficiency measurements and the efficiency of • the solar cells will be measured. **Key Results Conclusions** Studying the effect of dopant concentration on the band The novel design of the graded layer will enhance the lightdiagram and the solar cell performance generated carriers absorption due to the novel grading design. Optimizing EQE measurements and optical characterization of The absence of the front contact and using only back contact will ٠ Ga2O3 and GaN. allow more light to be absorbed in this solar cell structure. Low temperature PL and XRD for thick graded $In_xGa_{1-x}N$. Surface characterization using AFM and SEM. **Future Work** —— Ga —— In Nextnano3 simulation for the band diagram Analyzing TEM images for the growth of graded InGaN material. of graded InGaN/GaN structure. SIMS measurements to determine the elements composition.

SIMS elemental concentration depth profiles for graded InGaN (0-100% In) on GaN substrate. The top layer is reverse graded InGaN (100%-70% In)

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